

S1 (arrow mark): HRs>99.9% @ 510-530 nm | GDDrs|<10fss + HTp>99% @ 1020-1060 nm, |GDDtp|<5fss, AOI=45°
 S2: Uncoated

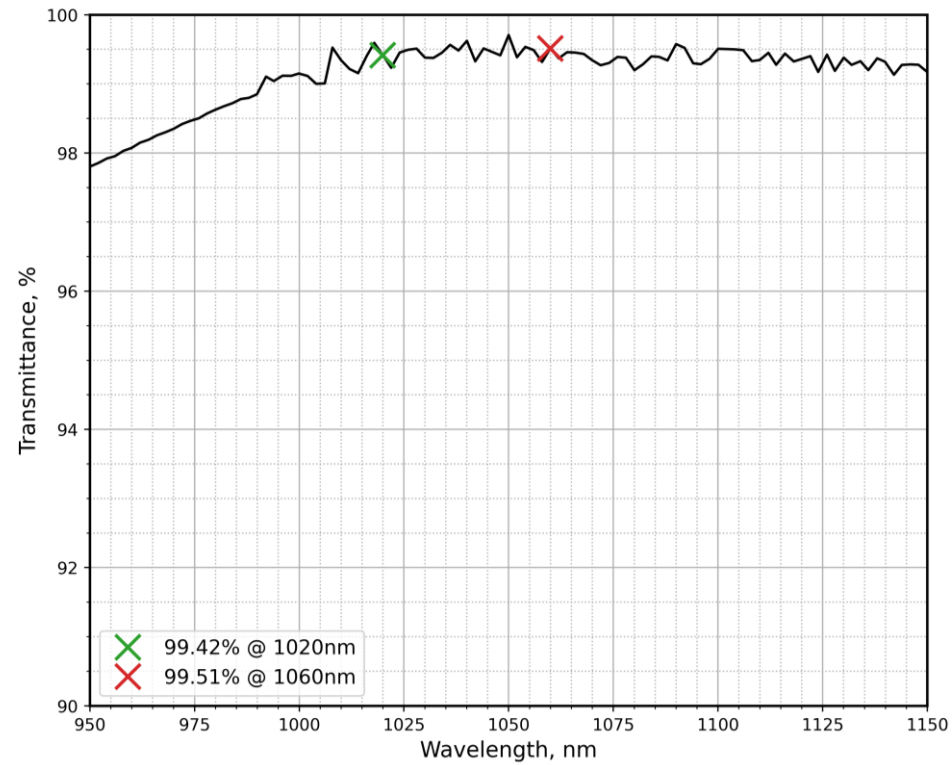


Fig. 1. PO5816 PAN6000 Tp i45

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow mark): HRs > 99.9% @ 510-530 nm | GDDrs < 10fss + HTp > 99% @ 1020-1060 nm, | GDDtp < 5fss, AOI = 45°
 S2: Uncoated

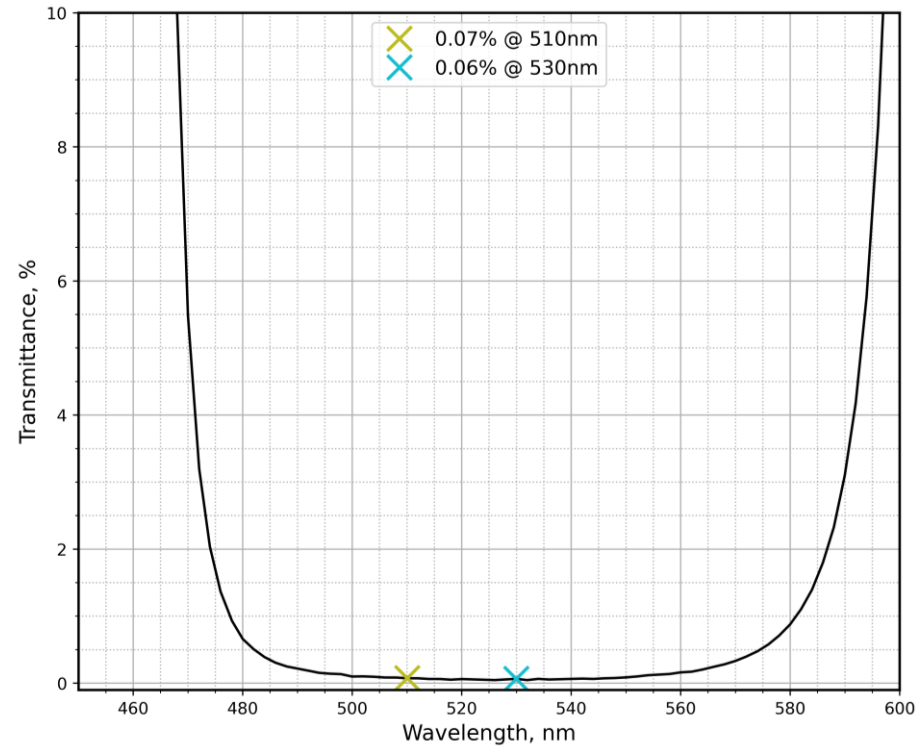


Fig. 2. PO5816 PAN6000 Ts i45

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/- 0.25%

S1 (arrow mark): HRs>99.9% @ 510-530 nm | GDDrs|<10fss + HTP>99% @ 1020-1060 nm | GDDtp|<5fss, AOI=45°
 S2: HRs>99.9% @ 510-530 nm | GDDrs|<50fss + HRp>99.8% | GDDrp|<35fss @ 1020-1060 nm, AOI=45°

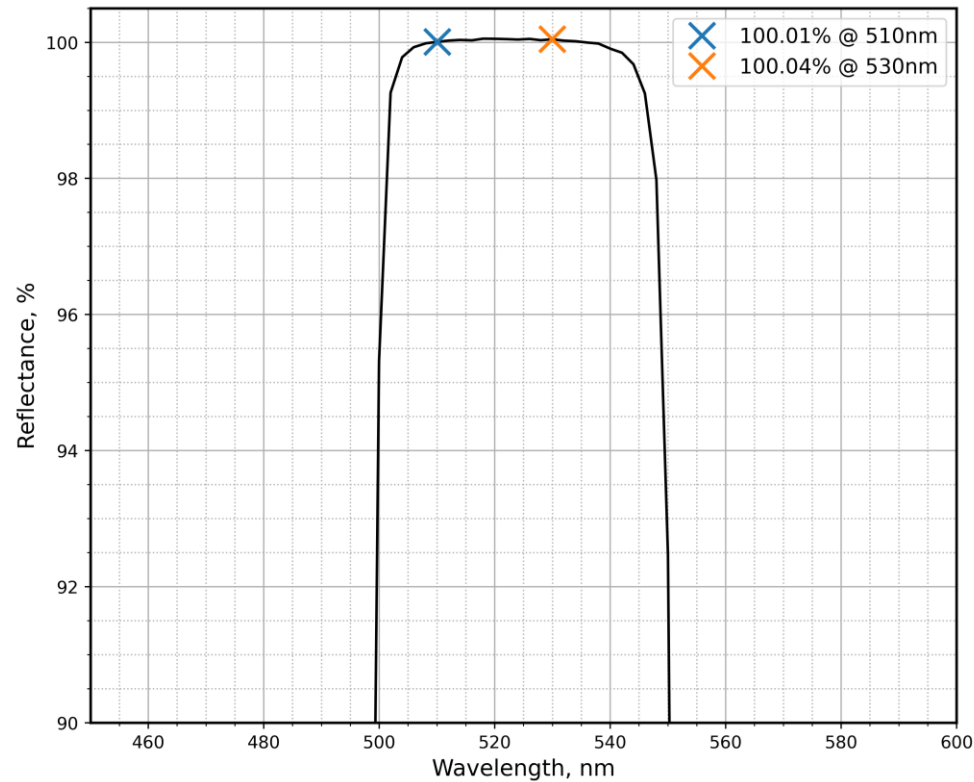


Fig. 3. PO5816 PAN6001 Rs i45 S2

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow mark): HRs>99.9% @ 510-530 nm | GDDrs|<10fss + HTP>99% @ 1020-1060 nm | GDDtp|<5fss, AOI=45°
 S2: HRs>99.9% @ 510-530 nm | GDDrs|<50fss + HRp>99.8% | GDDrp|<35fss @ 1020-1060 nm, AOI=45°

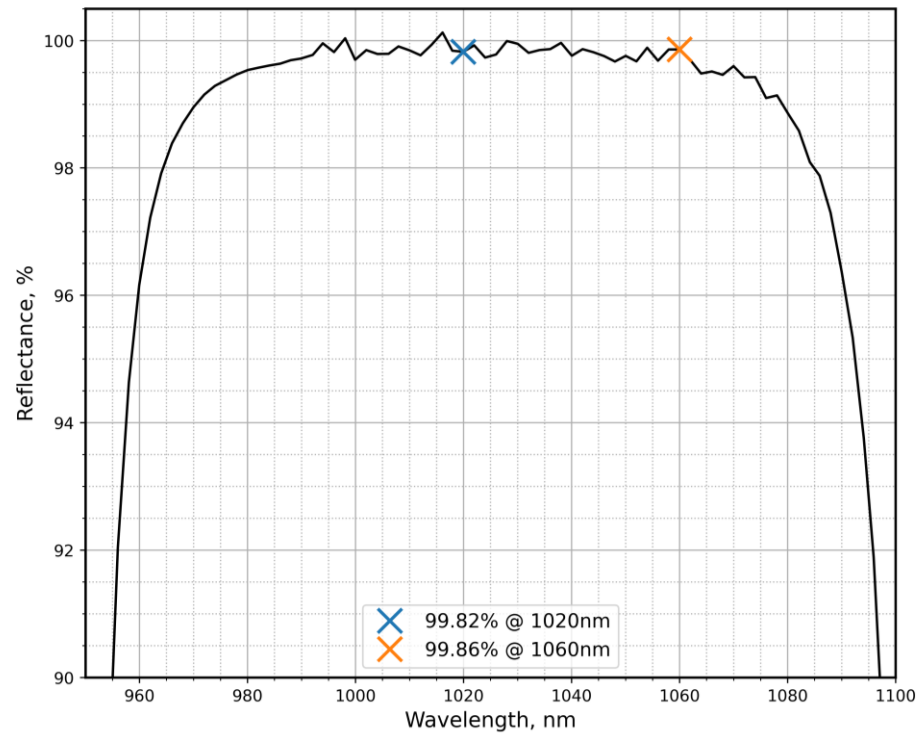


Fig. 4. P05816 PAN6001 Rp i45 S2

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%